

Analysis Plan during INTT workshop

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- Analysis topic (Write your topic)
Half-entry issue

- Current knowledge/status of this topic (What you know/have)
Analysis of a beam data from p+p run showed 1.3%(38 chips) half-entries

- Goal for the workshop (Your goal; Please write down with priority)
 1. Estimate the number of chips with half-entries from noise data
 2. Confirm that the half-entries were restored by analyzing the data with different Digital-Control
 3. Identify the parameters to restore each chips

- Milestones to reach to your goal
(Write down what you need to learn/study for reaching to your goal)
 1. Learn how to make a root file of the data acquired by INTT actual equipment
 2. Need to compensate for chip type dependence and layer dependence
 3. Learn Fun4all to reproduce the result similar to ROOT

1.Profile/Hobby

Profile

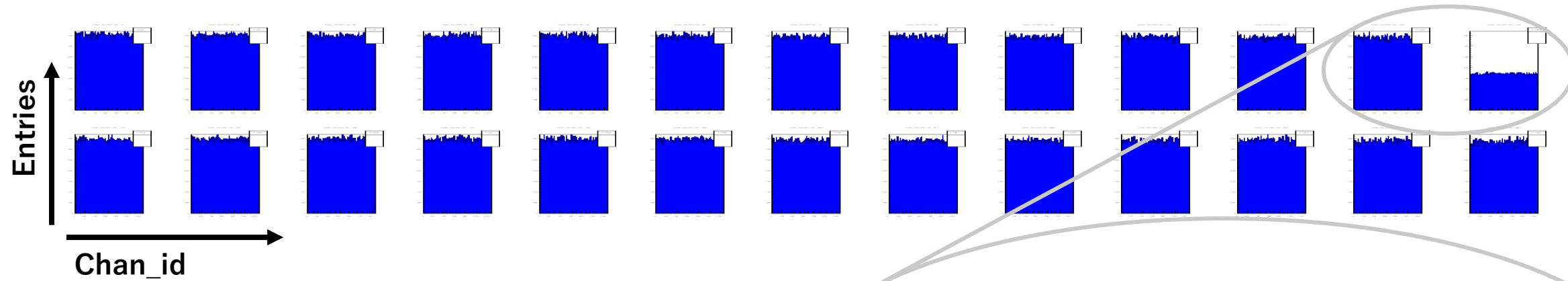
- Date of birth : 05/08/2002
- I passed the graduate school exam!

Hobby

- Football, Futsal, Japanese anime and magic
- Cycling



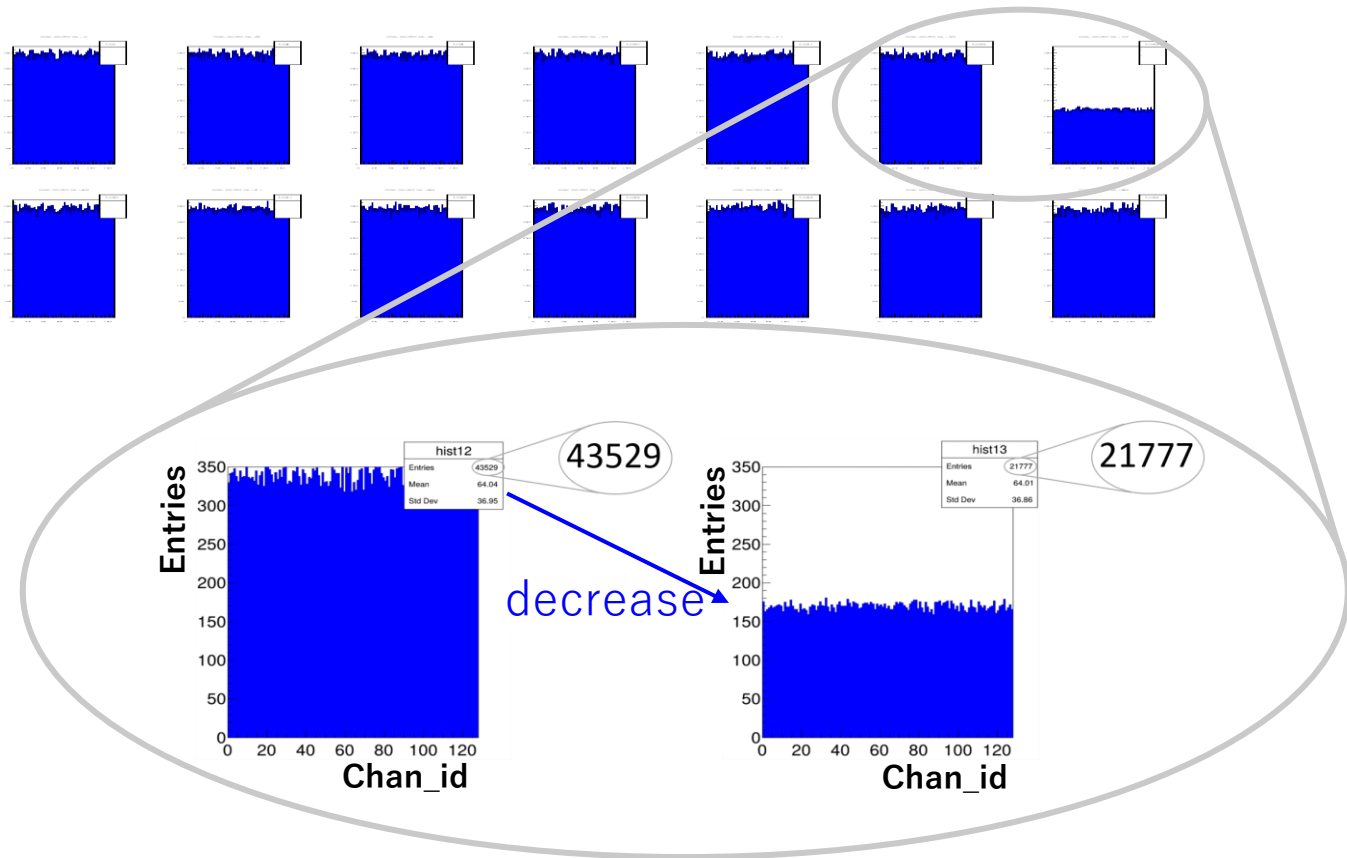
2. In my graduation study



The data from Calibration tests should yield a similar number of entries per chip or channel.

↓ However

Several chips were observed with only half the number of entries detected. We call this **the half-entry issue**.



2. In my graduation study

Focus on transfer method

- There are two data output lines from a FPHX-chip to the ROC

Hypothesis

- The FPHX-chip is equipped with a feature called Digital-Control, one of which is a mode that clones data and sends them to both output lines.

Result

- The number of data on all chips with half-entry at the Riken could be restored to normal.

